



PATENT
Attorney Docket No.: 16869P-004610US
Client Ref. No.: 219800332US2

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Yukihiro Shibata et al.

Application No.: 10/761,493

Filed: January 20, 2004

For: METHOD AND APPARATUS FOR
OBSERVING AND INSPECTING
DEFECTS

Customer No.: 20350

Confirmation No. 4371

Examiner: Tu T. Nguyen

Technology Center/Art Unit: 2877

AMENDMENT UNDER 37 CFR 1.116
EXPEDITED PROCEDURE EXAMINING
GROUP 2877

Mail Stop AF

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

In response to the Final Office Action mailed August 8, 2005 on the above-referenced application, please enter the following amendments and remarks:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 5 of this paper.